

Supplementary information

**CH₃NH₃⁺ and Pb Immobilization Through PbI₂ Binding by
Organic Molecule Doping for Homogeneous Organometal Halide
Perovskite films**

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Supplementary References

Supplementary Notes

1. Experimental Methods

1.1 Materials

MAI ($\geq 99\%$) and PMMA (average $M_w \sim 120,000$) were purchased from Sigma-Aldrich. PCBM ($>99.5\%$) and Spiro-OMeTAD ($>99\%$) were purchased from Lumtec. PbI_2 (99.9985%) and SnO_2 colloidal precursor (tin (IV) oxide, 15% in H_2O colloidal dispersion) were purchased from Alfa Aesar. N,N-Dimethylformamide (DMF, 99.8%, Extra Dry), dimethyl sulfoxide (DMSO, $>99.7\%$, Extra Dry) and chlorobenzene (CB, 99.8%, Extra Dry) solvents were purchased from Acros Organics. All materials were used without further purification.

For $MAPbI_3$ perovskite precursor solutions (40 wt%), PbI_2 and MAI were dissolved in DMF and DMSO mixed solution (2:1 v/v) with a molar ratio of 1:1, and then stirred at $60^\circ C$ for 8 h in glovebox. The CB solution with PCBM, PMMA or PCBM+PMMA for doping was prepared with a total mass concentration of 0.1 wt%. SnO_2 precursor solution was prepared by diluting purchased SnO_2 colloidal precursor with H_2O (5:1 v/v). The synthesis method of Spiro-OMeTAD precursor solution is based on the previous literature.¹

1.2 Film fabrications and characterizations

All the undoped and doped $MAPbI_3$ films were prepared on the substrates of FTO-coated glass by a one-step solution process using spin-coating method with anti-solvent method. The prepared $MAPbI_3$ precursor solution was dropped on the FTO substrate by the spin-coating method with an initial speed of 3000 rpm and an acceleration rate of 2000 rpm/s for 35 s. The anti-solvent method was applied during the spin coating, in which a small amount (150-200 μL) of CB solutions was dropped on the spinning substrate during the last 10 s. The doped $MAPbI_3$ films were obtained by using the CB solution with PCBM, PMMA or PCBM+PMMA.

The XPS C core-level and valance band spectra were obtained by using an ESCALAB 250 (Thermo-VG Scientific). The PL decay of $MAPbI_3$ films was studied by a FLS980

Spectrometer (Edinburgh) in air at room temperature. The MAPbI₃ films were photoexcited using a laser head (EPL-405) with a wavelength of 406.2 nm and a pulse width of 58.8 ps. The crystalline structures of MAPbI₃ films were obtained by XRD (D-MAX 2200 VPC) with a Cu-K α radiation operated at 40 kV and 26 mA. The chemical mappings were obtained by nano-IR2 (Anasys Instruments) equipped with a pulsed quantum cascade laser (913-1900 cm⁻¹). The laser power was set as 67.57% with the pulse rate of ~300 kHz to enhance IR signal. The surface topography and chemical mappings were collected simultaneously by AFM-IR with a tapping mode using an Au-coated NIR2 probe (Anasys, PR-EX-TnIR-A-10) with a force constant of 1-7 nN/nm and a frequency of ~75 kHz. The FTIR spectra were obtained by an infrared spectrometer (Frontier). The SEM images were obtained by Quanta 250FEG (FEI). The SKPM measurements were performed in air using a Scanning Probe Microscope (MFP-3D Asylum Research). The surface potential images were collected by a tapping mode using a sharp conductive single crystal diamond probe (Adama, Au coating, 2.8 N/m, 65 kHz). The UV-Vis absorption spectra were measured using an UV-VIS-NIR spectrophotometer (UV 3600).

1.3 Solar cell device fabrications and measurements

FTO-coated glass substrate (NSG, 14 (\pm 1.5) Ω /sq, T>85 %, 20*20 mm) was washed using cleaning powder, cleaned successively with ethyl alcohol, acetone, isopropanol and deionized water in an ultrasonic bath for 15 min each, and finally flushed with nitrogen. After UV-ozone surface treatment for 30 min, a SnO₂ thin-film was deposited onto the cleaned FTO substrate by using spin-coating method (3000 rpm for 30 s), and afterwards annealed at 150°C for 30 min on a heating plate in air. After cooling down to room temperature, the SnO₂-coated FTO substrate was treated by UV-ozone for 5 min and transferred to glovebox. The PCBM (2 wt % in CB solvent) layer was spin-coated (3000 rpm 30 s) onto the SnO₂-coated FTO, and then annealed at 110 °C for 30 min. The prepared MAPbI₃ precursor solution was dropped on the FTO/SnO₂/PCBM substrate by the spin-coating method with an initial speed of 3000 rpm and

an acceleration rate of 2000 rpm/s for 35 s. The anti-solvent method was applied during the spin coating of the MAPbI₃ layer, in which a small amount (150-200 μ L) of CB solutions was dropped on the spinning substrate during the last 10 s of the spin-coating process. The doped MAPbI₃ layers were obtained by using the CB solution with PCBM, PMMA or PCBM+PMMA. After spin-coating, the FTO/SnO₂/PCBM/MAPbI₃ substrate was put on a heating plate at 100 °C for 40 min. Spiro-OMeTAD as the hole transfer layer was coated on MAPbI₃ with a spin speed of 3000 rpm for 30 s, without further annealing treatment. A 40 nm Au (99.999%) layer was eventually deposited by thermal evaporation with a metal pattern plate to form the planar PSCs with the configurations of FTO/SnO₂/PCBM/perovskite/Spiro-OMeTAD/Au.

The *J-V* characteristics of PSC devices were obtained by using a Keithley 2400 Semiconductor Characterization System under the illumination of one-sun AM1.5G (100 mW/cm²) solar simulator (Abet Technologies Sun 3000). The light intensity was calibrated by a KG-5 crystalline silicon diode. A shadow mask (circular aperture, 0.07 cm²) was used for the calibration of the active area. A voltage step of 30 mV was fixed in the reverse scans (from 1.2 V to -0.2 V) and the forward scans (from -0.2 V to 1.2 V). The EQE spectra were obtained by using a quantum efficiency measurement system QEXL (PV measurements), and calibrated by a standard single-crystal silicon reference cell. All the device measurements were carried out in air conditions.

2. DFT Methods

Density functional theory (DFT) calculations were performed using the Vienna ab initio simulation package (VASP)² with the projector-augmented-wave (PAW)³ approach. The exchange–correlation contributions were considered via the Perdew-Burke-Ernzerhof (PBE)⁴ functional within the generalized gradient approximation (GGA). The plane wave basis set-up to an energy cut-off of 500 eV was utilized throughout all the calculations. For the geometrical optimizations, the structures were allowed to relax until the total energy converged below 10⁻⁶

eV per atom and the forces converged below 0.01 eV Å⁻¹. Van der Waals forces were accounted for by applying the DFT-D3 method of Grimme.^{5,6} MAPbI₃ with 1 × 1 × 2 supercell was employed in our calculations, which containing 48 atoms in the defect-free structure. A 6 × 6 × 4 Monkhorst-Pack k-point grid was used for the geometrical optimization and density of states, while 10 k-point paths between adjacent k-point along the high symmetry lines within the first Brillouin zone were used to generate the band structure. To visualize the atomic structures in DFT modeling, the atoms in MAPbI₃, PCBM, and PMMA are depicted as spheres and colored as follows: Carbon (C): brown; Nitrogen (N): blue; Hydrogen (H): white; Lead (Pb): gray; Iodine (I): purple; Oxygen (O): red.

The formation free energies for MA vacancy ($\Delta G_{V_{MA}}$) were calculated as

$$\Delta G_{V_{MA}} = \Delta E_{V_{MA}} + \Delta E_{ZPE} - T\Delta S$$

where $\Delta E_{V_{MA}}$ is the formation energy for MA vacancy, ΔE_{ZPE} and ΔS are the zero-point energy difference and entropy difference between the MAPbI₃ with MA vacancy and the defect-free MAPbI₃, and T is the ambient temperature as 298.15 K. The formation energy for MA vacancy $\Delta E_{V_{MA}}$ was obtained by

$$\Delta E_{V_{MA}} = (E_{V_{n*MA}} + nE_{MAI}) - (E_{\text{defect-free}} + \frac{n}{2}E_{I_2(g)})$$

where n is the number of MA vacancies. The $E_{V_{n*MA}}$, E_{MAI} , $E_{\text{defect-free}}$, and $E_{I_2(g)}$ are the total energy of MAPbI₃ with the MA vacancies, the average unit energy of one MAI in bulk phase, the total energy of defect-free MAPbI₃, and the energy of an I₂ molecule in gas phase, respectively. As the vibrational frequency and entropy of crystal structure in the solid state are small, the difference in zero-point energy is $\Delta E_{ZPE} \approx -\frac{n}{2}E_{ZPE}^{I_2}$ and the entropy difference is

$\Delta S \approx -\frac{n}{2}S_{I_2}^0$, where $E_{ZPE}^{I_2}$ is the zero point energy of the I₂ molecule in the gas phase, $S_{I_2}^0$ is the entropy of the I₂ molecule in the gas phase at the standard conditions.^{7,8}

The formation free energies for Pb-occupied MA vacancy ($\Delta G_{\text{Pb}_{\text{MA}}}$) were derived as

$$\Delta G_{\text{Pb}_{\text{MA}}} = \Delta E_{\text{Pb}_{\text{MA}}} + \Delta E_{\text{ZPE}} - T\Delta S$$

where $\Delta E_{\text{Pb}_{\text{MA}}}$ is the formation energy for Pb-occupied MA vacancy, ΔE_{ZPE} and ΔS are the zero-point energy difference and entropy difference between MAPbI₃ with Pb-occupied MA vacancy and unoccupied MA vacancy, and T is the ambient temperature as 298.15 K. The formation energy for Pb-occupied MA vacancy $\Delta E_{\text{Pb}_{\text{MA}}}$ can be given as

$$\Delta E_{\text{Pb}_{\text{MA}}} = (E_{n^*\text{Pb}_{\text{MA}}} + nE_{\text{I}_2(\text{g})}) - (E_{\text{V}_{n^*\text{MA}}} + nE_{\text{PbI}_2})$$

where n is the number of Pb-occupied MA vacancies. The $E_{n^*\text{Pb}_{\text{MA}}}$, $E_{\text{I}_2(\text{g})}$, $E_{\text{V}_{n^*\text{MA}}}$, and E_{PbI_2} are the total energy of MAPbI₃ with Pb-occupied MA vacancies, the energy of an I₂ molecule in gas phase, the total energy of MAPbI₃ with MA vacancies, and the energy of PbI₂, respectively. As the vibrational frequency and entropy of crystal structure in the solid state are small, the difference in zero-point energy is $\Delta E_{\text{ZPE}} \approx nE_{\text{ZPE}}^{\text{I}_2}$ and the entropy difference is $\Delta S \approx nS_{\text{I}_2}^0$.

The binding free energies ($\Delta G_{\text{binding}}$) of the interactions between the PbI₂ and the doped organic molecules (PCBM or PMMA) were defined as

$$\Delta G_{\text{binding}} = \Delta E_{\text{binding}} + \Delta E_{\text{ZPE}} - T\Delta S$$

where $\Delta E_{\text{binding}}$ is the binding energy, ΔE_{ZPE} and ΔS are the zero-point energy difference and entropy difference, T is the ambient temperature as 298.15 K. The binding energy $\Delta E_{\text{binding}}$ for PbI₂ interacting with PCBM or PMMA can be given by

$$\Delta E_{\text{binding}} = E_{\text{PbI}_2 + \text{PCBM/PMMA}} - E_{\text{PCBM/PMMA}} - E_{\text{PbI}_2}$$

where $E_{\text{PbI}_2 + \text{PCBM/PMMA}}$, $E_{\text{PCBM/PMMA}}$, and E_{PbI_2} are the total energy of PbI₂ binding with PCBM or PMMA, the energy of PCBM or PMMA, and the energy of PbI₂, respectively. As PbI₂,

PCBM and PMMA are not in the gaseous form in MAPbI₃ films, the differences in vibrational frequencies and entropy are negligible, and hence $\Delta G_{\text{binding}} \approx \Delta E_{\text{binding}}$.

Supplementary Tables

Table S1. Photoexcited carrier lifetime measured by PL decays of MAPbI₃ films. Different doping cases of “undoped”, “PCBM doped”, “PMMA doped” and “PCBM+PMMA doped” are studied. The mass ratios of 7:3, 1:1 and 3:7 between PCBM and PMMA are considered. Short lifetimes τ_1 and long lifetimes τ_2 associated with the corresponding relative amplitudes of A_1 and A_2 were obtained by fitting a bi-exponential equation as $Y(t)=A_1\exp(t/\tau_1)+A_2\exp(t/\tau_2)$. Average lifetimes were calculated by the equation of $\tau=A_1\tau_1+A_2\tau_2$. The mean standard deviations were derived from five independent samples of each case.

	A_1 (%)	τ_1 (ns)	A_2 (%)	τ_2 (ns)	Average lifetimes τ (ns)
Undoped	37 (± 6)	65 (± 17)	63 (± 6)	328 (± 43)	229 (± 20)
PCBM doped	17 (± 11)	146 (± 65)	83 (± 11)	696 (± 36)	599 (± 39)
PMMA doped	7 (± 2)	73 (± 20)	93 (± 2)	516 (± 35)	484 (± 37)
PCBM:PMMA =7:3 (w/w)	14 (± 11)	140 (± 83)	86 (± 11)	808 (± 103)	712 (± 32)
PCBM:PMMA =1:1(w/w)	14 (± 6)	166 (± 66)	86 (± 6)	892 (± 104)	788 (± 73)
PCBM:PMMA =3:7(w/w)	10 (± 7)	229 (± 103)	90 (± 7)	1183 (± 132)	1083 (± 69)

Table S2. Lattice constants, unit cell volumes and c/a values by fitting XRD patterns. The structural parameters of single-crystal MAPbI₃ originate from the work by Baikie, T. et al.⁹

	a (Å)	b (Å)	c (Å)	Unit Cell Volume (Å ³)	c/a
Single crystal⁹	8.8743	8.8743	12.6708	997.86605	1.42781
Undoped	8.86876	8.86876	12.61467	992.20504	1.42237
PCBM doped	8.87135	8.87135	12.62934	993.93936	1.42361
PMMA doped	8.87119	8.87119	12.62855	993.84245	1.42355
PCBM+PMMA doped	8.87214	8.87214	12.64694	995.50228	1.42547

Table S3. Formation free energy of one MA vacancy (V_{MA}) in MAPbI_3 .

MAPbI₃ with one MA vacancy (eV)	
Defect free MAPbI₃	-208.19
V_{MA}	-166.01
MAI	-42.29
$0.5 \cdot \text{I}_2$	-1.32
ΔE_{ZPE}	0.01
$T\Delta S$	-0.40
Formation free energy	1.62
2*Formation free energy	3.24

Table S4. Formation free energy of two adjacent MA vacancies (V_{2*MA}) in MAPbI₃.

MAPbI ₃ with two adjacent MA vacancy (eV)	
Defect free MAPbI ₃	-208.19
V_{2*MA}	-123.75
$2*MAI$	-84.58
I_2	-2.65
ΔE_{ZPE}	0.02
$T\Delta S$	-0.80
Formation free energy	3.33

Table S5. Formation free energy of one Pb-occupied MA vacancy (Pb_{MA}) in MAPbI_3 .

MAPbI_3 with one Pb-occupied MA vacancy (eV)	
V_{MA}	-166.01
Pb_{MA}	-170.38
PbI_2	-7.39
I_2	-2.65
ΔE_{ZPE}	-0.02
$T\Delta S$	0.80
Formation free energy	-0.45
2*Formation free energy	-0.90

Table S6. Formation free energy of two adjacent Pb-occupied MA vacancies (Pb_{2^*}MA) in MAPbI_3 .

MAPbI_3 with two adjacent MA vacancies occupied by Pb atoms (eV)	
V_{2^*}MA	-123.75
Pb_{2^*}MA	-133.93
2^*PbI_2	-14.78
2^*I_2	-5.30
ΔE_{ZPE}	-0.04
$T\Delta S$	1.60
Formation free energy	-2.34

Table S7. Binding free energies for PbI₂ and doped organic molecules.

	Case 1:	Case 2:
	PbI₂ binding with PCBM	PbI₂ binding with PMMA
	(eV)	(eV)
PCBM/PMMA	-704.21	-87.63
PbI₂	-7.39	-7.39
PCBM/PMMA+PbI₂	-712.19	-95.55
Binding free energy	-0.59	-0.53

Supplementary Figures

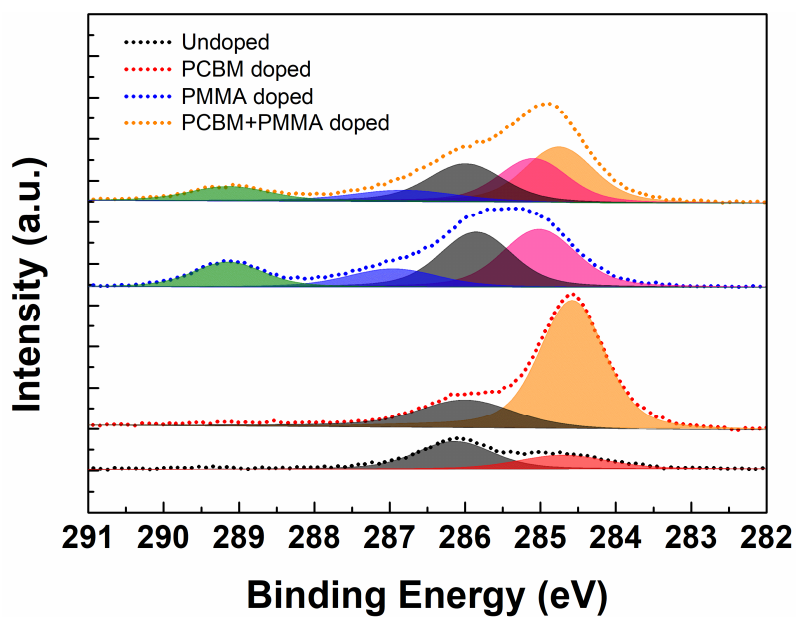


Fig. S1. XPS spectra of undoped and doped MAPbI₃ films. The carbon core-level spectra for MA state (~286 eV, black peak) in MAPbI₃ films, C-CH₃ (~285 eV, pink peak), O-CH₃ (286.8 eV, blue peak) and C-C=O (~289 eV, green peak) states in PMMA, and C₆₀ state (284.6 eV, orange peak) in PCBM are analyzed, which validate the distribution of PCBM and PMMA in the doped MAPbI₃ films.

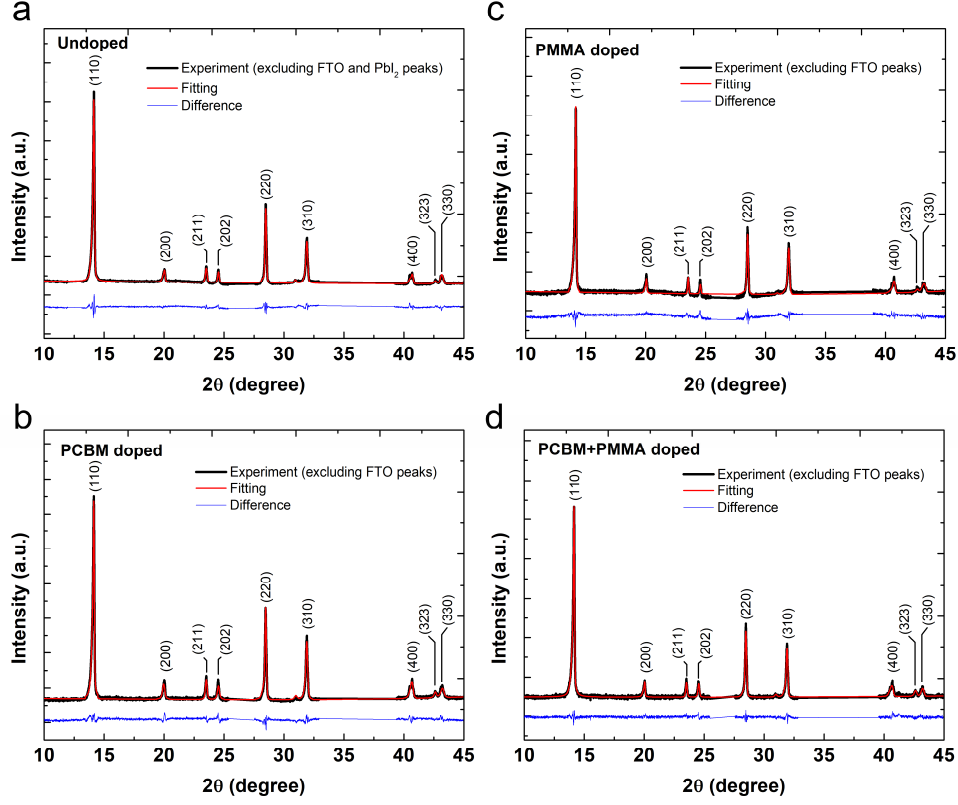


Fig. S2. GSAS fitting XRD patterns of undoped (a), PCBM doped (b), PMMA doped (c) and PCBM+PMMA doped (d) MAPbI₃ films. For fitting the structural parameters of MAPbI₃ films, nine XRD patterns for each doping case of MAPbI₃ films were selected with the peaks of PbI₂ and FTO excluded. The experimental XRD patterns and the fitting curves are plotted as the black and red curves, respectively. The blue curves show the differences between the experimental XRD patterns and the fitting curves.

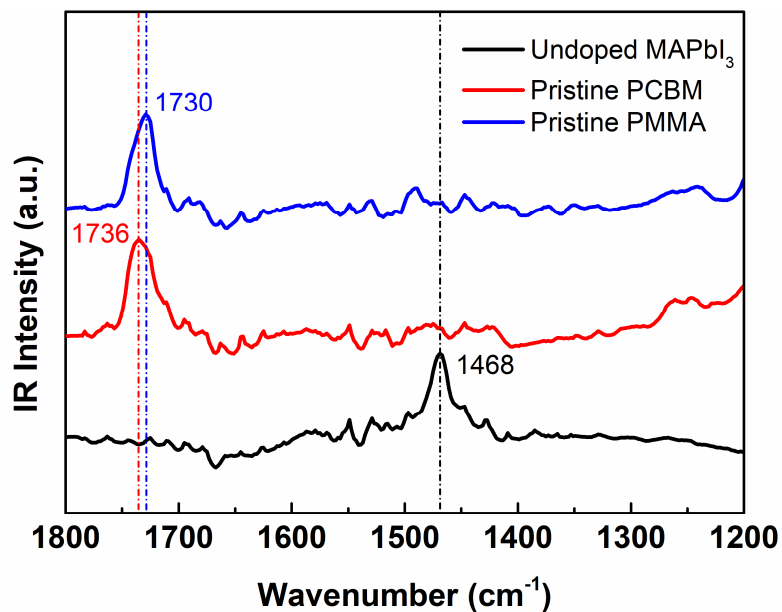


Fig. S3. Normalized IR spectra of undoped MAPbI₃ film, pristine PCBM and PMMA. The IR data was obtained by the contact-mode AFM-IR measurement. The characteristic IR peaks at 1468 cm⁻¹, 1736 cm⁻¹ and 1730 cm⁻¹, which correspond to the C-H bending of MA cations, the C=O stretching of PCBM and PMMA, were adopted to probe the distribution of MA cations, PCBM and PMMA molecules in MAPbI₃ films, respectively.

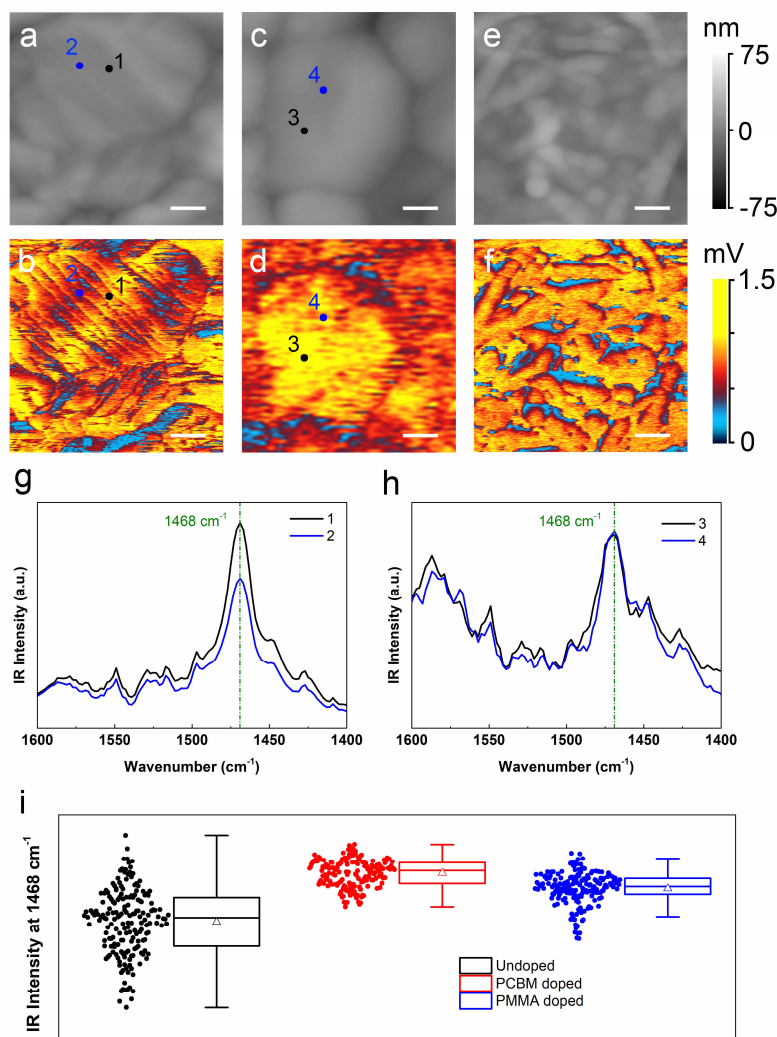


Fig. S4. MA distribution in undoped and doped MAPbI₃ films by AFM-IR. (a-f) Magnified images of surface topography and chemical distribution for the regions within the boxes of the undoped (a,b), PCBM doped (c,d) and PMMA doped (e,f) MAPbI₃ films in Figs. 3a-f, respectively. The scale bars are 100 nm. (g,h) Localized IR spectra from the representative sites marked in Figs. S4a-d. (i) Statistical diagram of the IR intensity at 1468 cm⁻¹ sampled from 182 sites for each doping cases. The IR data are shown as solid circles. The boxplots show the maximum, upper quartile, median, lower quartile and minimum from top to bottom, respectively. The mean values are depicted as hollow triangles.

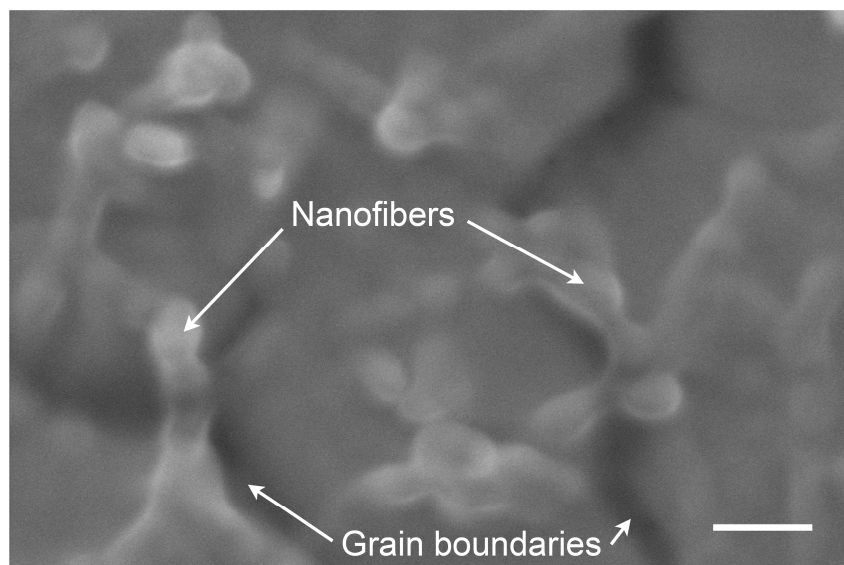


Fig. S5. High-resolution SEM image of PCBM+PMMA doped MAPbI₃ film. The scale bar is 100 nm.

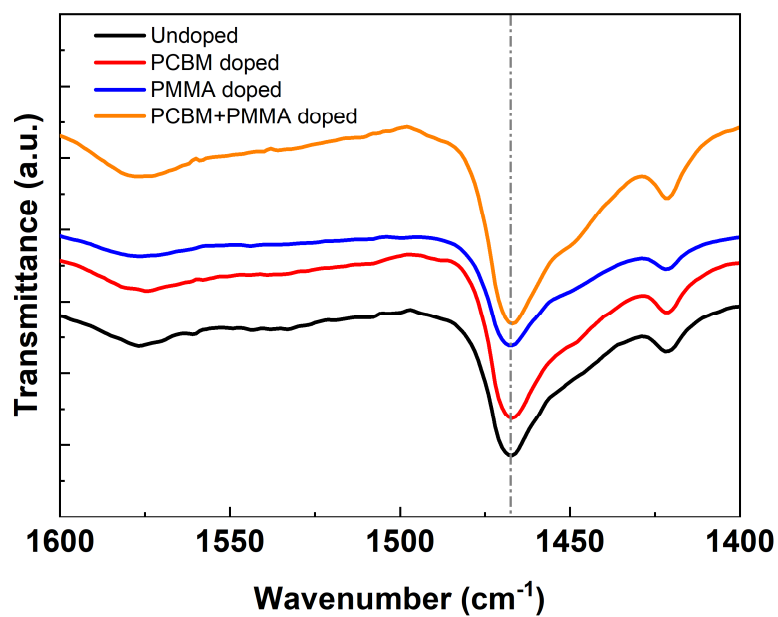


Fig. S6. FTIR spectra of undoped, PCBM doped, PMMA doped and PCBM+PMMA doped MAPbI₃ films. The representative IR peaks at 1468 cm⁻¹ marked by the dash-dot line corresponds to the C-H bending of MA cations in MAPbI₃.

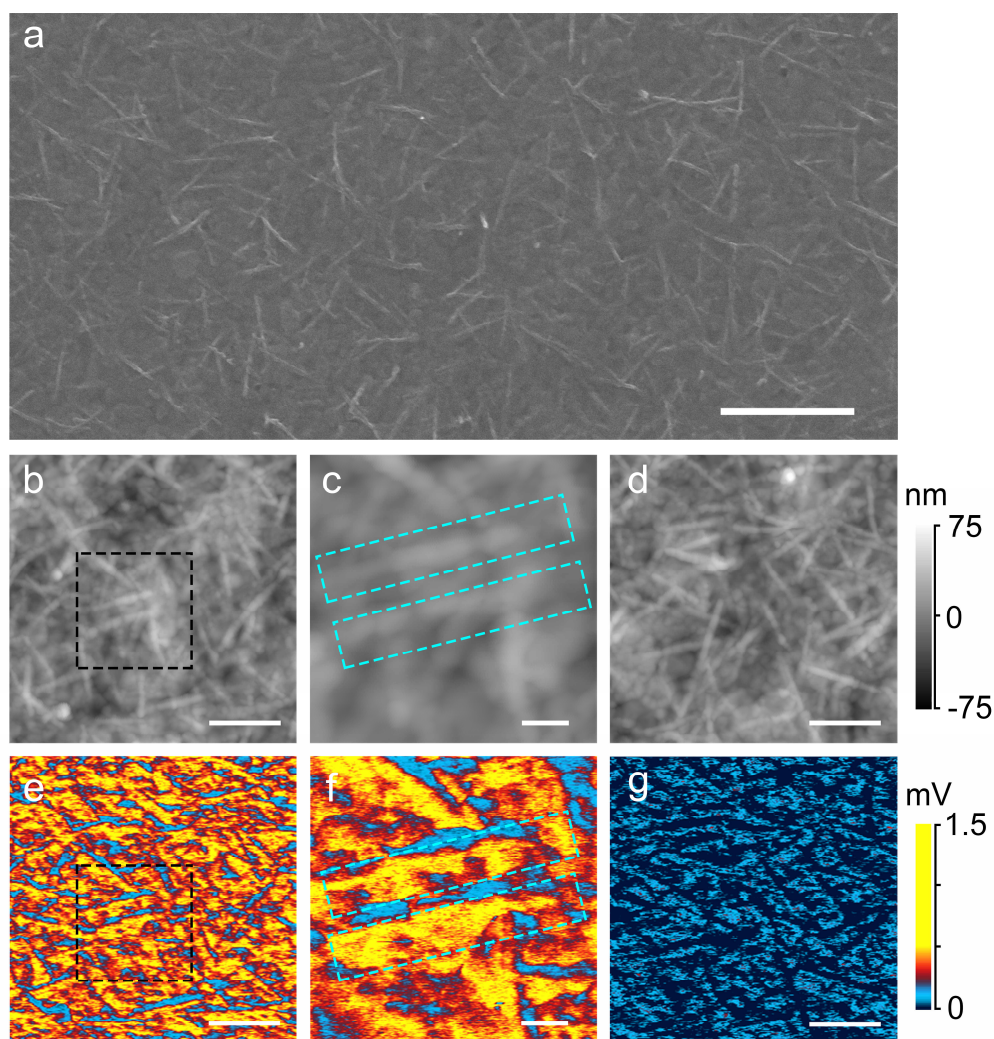


Fig. S7. Surface topography and chemical distribution of PMMA doped MAPbI₃ films after 20-times CB washing. (a) SEM image of surface topography. (b-g) AFM-IR images of surface topography (b-d) and chemical distribution (e-g). (e) and (f) are the MA mappings corresponding to the regions of (b) and (c), respectively. (c) and (f) magnify the same region within the black dashed boxes in (b) and (e). Two parallel nanofibers are highlighted by blue dashed boxes in the magnified images of (c) and (f). (g) is the PMMA mapping corresponding to the region in (d). The size bars are 1 μm (a), 500 nm (b,d,e,g) and 100 nm (c,f).

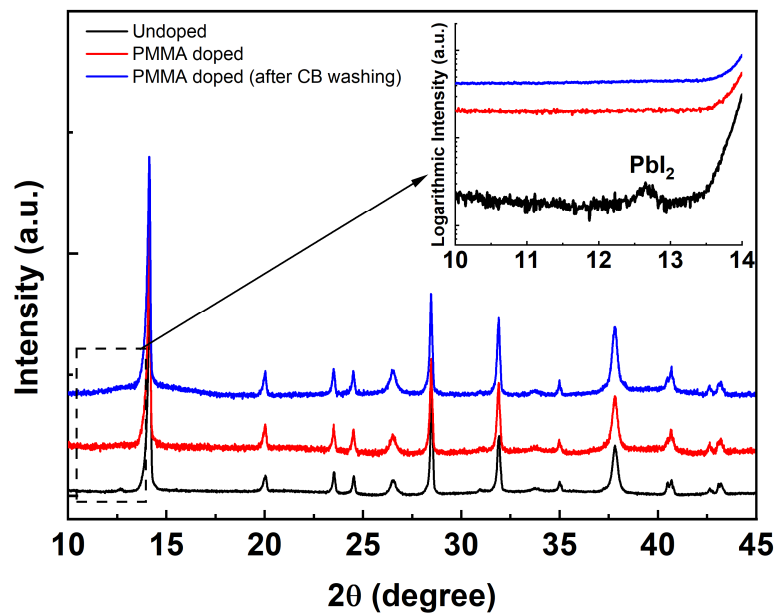


Fig. S8. XRD patterns of PMMA doped MAPbI₃ films before and after CB washing. The black, red and blue curves are the XRD patterns of the undoped MAPbI₃ film, the PMMA doped MAPbI₃ film before CB washing and the PMMA doped MAPbI₃ film after CB washing, respectively. The inset magnifies the range of 2θ from 10° to 14° within the dashed box.

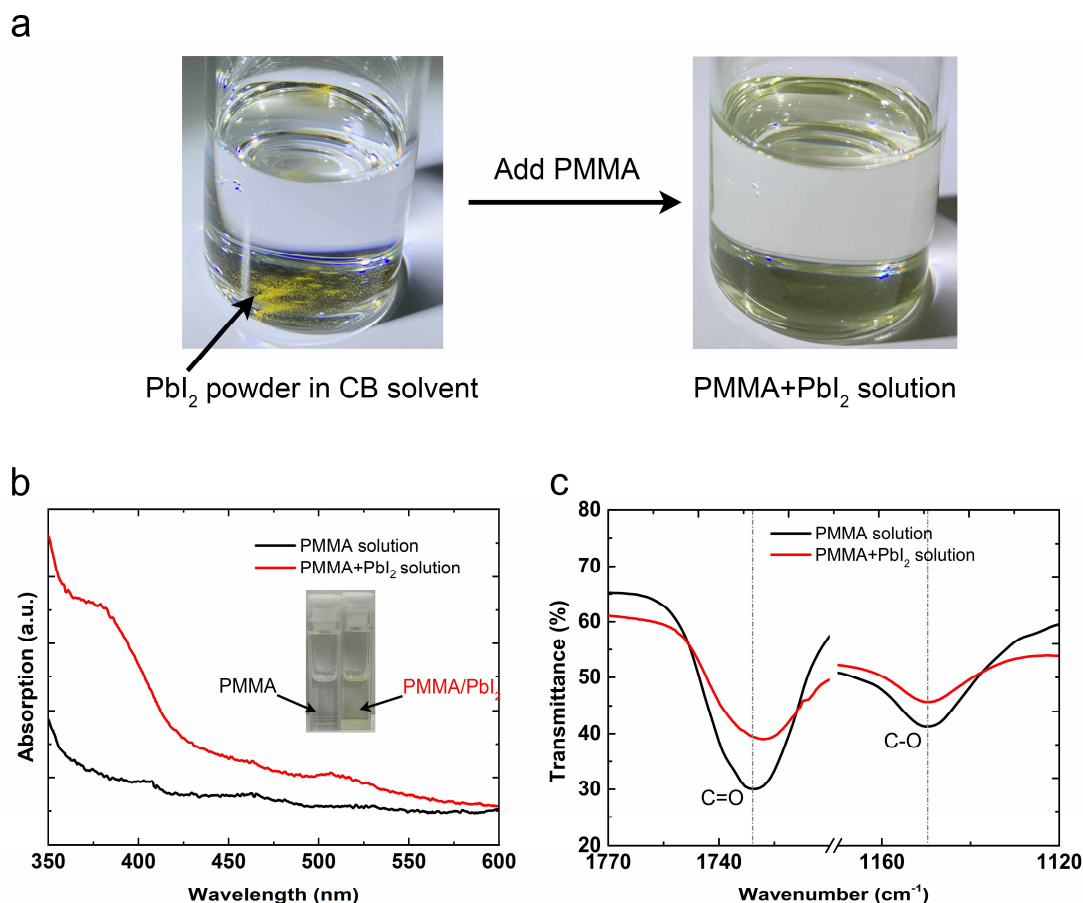


Fig. S9. Dissolution of PMMA-PbI₂ adducts in CB solvent. (a) Adding PMMA into the CB with the sediment of PbI₂ powder. The PbI₂ sediment disappears in the CB solvent added by PMMA. (b) UV-Vis absorption spectra of PMMA and PMMA+PbI₂ solutions. The PMMA solution represents the solution in which the PMMA dissolves in CB solvent. The PMMA+PbI₂ solution is the solution shown on the right of (a) in which the PMMA is added into the CB solvent with the PbI₂ sediment fully dissolved. The inset shows the PMMA and PMMA+PbI₂ solutions in quartzose cuvettes. Comparing with the case of the PMMA solution (black curve), the UV-Vis absorption spectrum of the PMMA+PbI₂ solution (red curve) shows a PbI₂ featured adsorption edge at ~450 nm, which proves the existence of PbI₂ in the PMMA+PbI₂ solution. (c) FTIR spectra of the PMMA and PMMA+PbI₂ solutions measured by using the corresponding solutions. The IR peaks of C=O bonds shift while the IR peaks of C-O bonds remain unchanged, which indicates that the PbI₂ can form adducts with PMMA and can be dissolved in CB solvent.

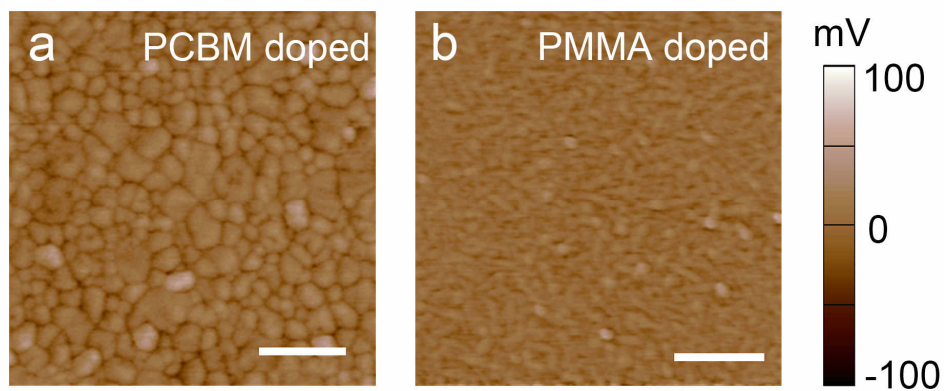


Fig. S10. Surface potential distribution of PCBM doped (a) and PMMA doped (b) MAPbI₃ films by SKPM. The scale bars are 1 μm .

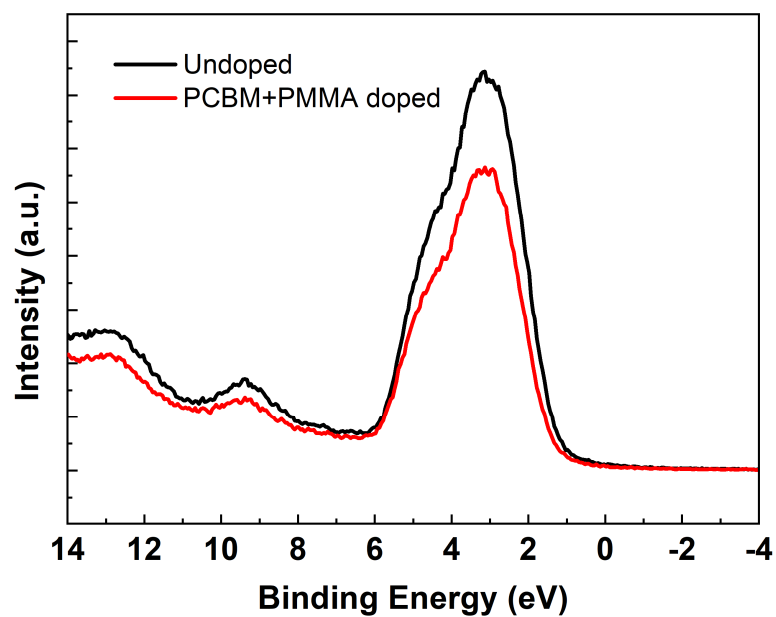


Fig. S11. Full-range XPS valence band spectra of undoped and PCBM+PMMA doped MAPbI₃ films. Fig. 7c magnifies the range from 4 eV to -1 eV.

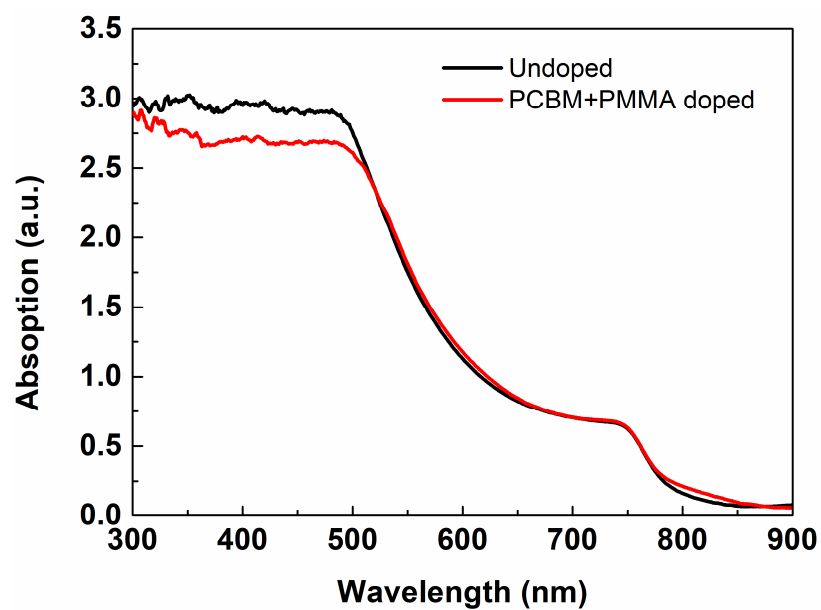


Fig. S12. UV-Vis absorption spectra of undoped and PCBM+PMMA doped MAPbI₃ films. The undoped and doped MAPbI₃ films show the same absorption edges at ~800 nm corresponding to the optical band gap of ~1.55 eV.

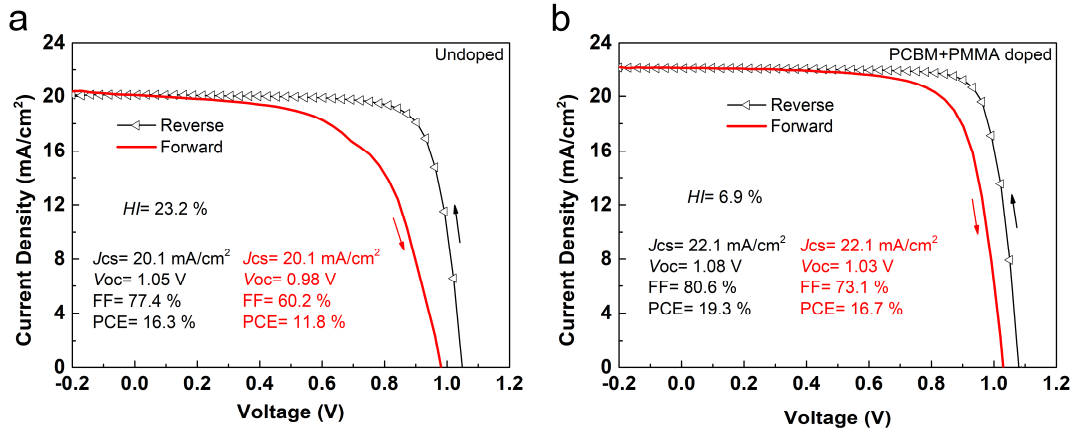


Fig. S13. J - V characteristics with reverse and forward scans for PSCs based on undoped (a) and PCBM+PMMA doped (b) MAPbI₃ films. The reverse mode scans from 1.2 V to -0.2 V, while the forward mode scans from -0.2 V to 1.2 V. J_{sc} , V_{oc} , FF and PCE denote short current density, open-circuit voltage, fill factor and photoelectric conversion efficiency, respectively. The hysteresis index (HI) was calculated¹⁰ by $HI = (J_R(0.8V_{oc}) - J_F(0.8V_{oc})) / (J_R(0.8V_{oc}))$, where $J_R(0.8V_{oc})$ and $J_F(0.8V_{oc})$ represent the J_{sc} at 80 % of V_{oc} at the reverse and forward scans, respectively.

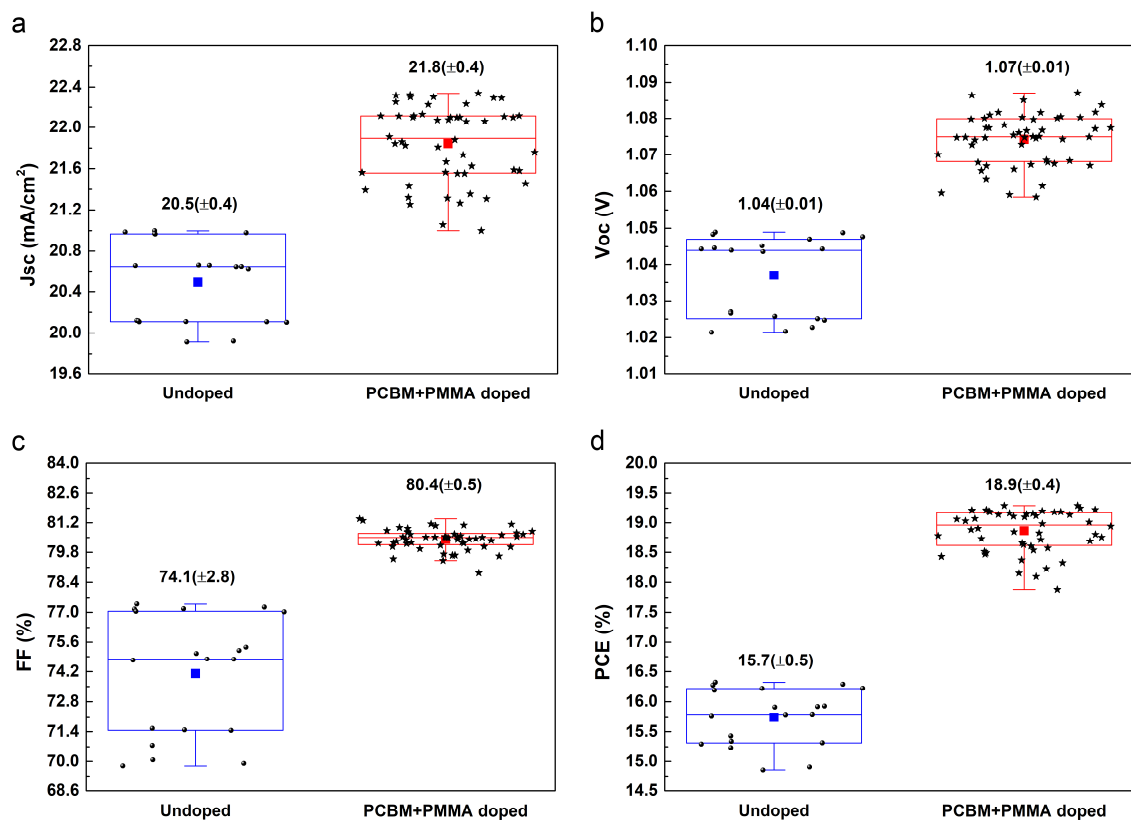


Fig. S14. Statistics of photovoltaic performance for PSCs based on undoped and PCBM+PMMA doped MAPbI₃ films. (a) J_{sc} . (b) V_{oc} . (c) FF. (d) PCE. Data for PSCs based on undoped and PCBM+PMMA doped MAPbI₃ films are shown as solid circles and stars, respectively. The boxplots show the maximum, upper quartile, median, lower quartile and minimum from top to bottom, respectively. The mean values are depicted as solid squares.

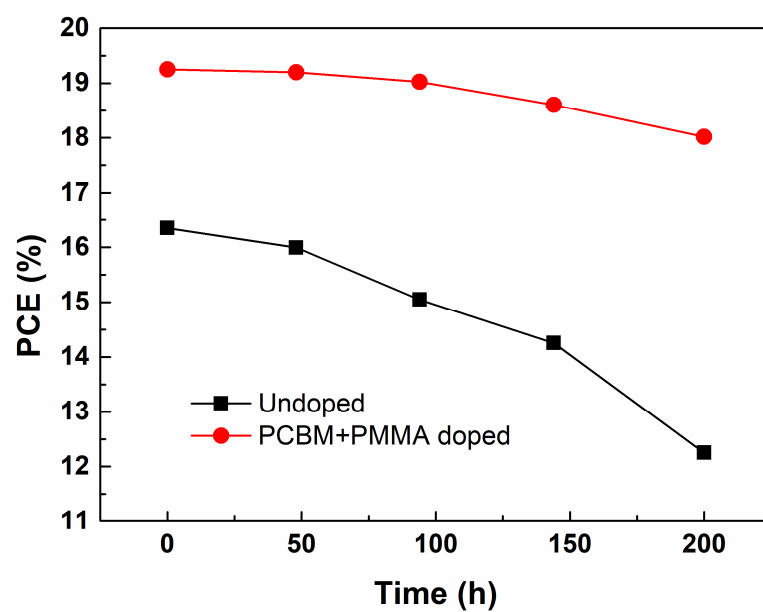


Fig. S15. Stability of unencapsulated PSCs based on undoped and PCBM+PMMA doped MAPbI₃ films. PCE evolution under ambient atmosphere with relative humidity (RH) of 60-70% without encapsulation.

Supplementary References

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